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(12) **United States Design Patent**
Ishii et al.

(10) **Patent No.:** **US D766,753 S**
(45) **Date of Patent:** **** Sep. 20, 2016**

(54) **OPTICAL MEASURING THEODOLITE USING LIGHT WAVE**

CPC G01C 1/00-1/14
See application file for complete search history.

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(56) **References Cited**

U.S. PATENT DOCUMENTS

(72) Inventors: **Mitsuo Ishii**, Tokyo (JP); **Takeo Aoki**,
Tokyo (JP)

D453,478 S * 2/2002 Ishii D10/69
D563,247 S * 3/2008 Ishii D10/66
D723,398 S * 3/2015 Ishii D10/66

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* cited by examiner

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(**) Term: **15 Years**

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(21) Appl. No.: **29/529,894**

(57) **CLAIM**

The ornamental design for an optical measuring theodolite using light wave, as shown and described.

(22) Filed: **Jun. 11, 2015**

DESCRIPTION

(30) **Foreign Application Priority Data**

Mar. 20, 2015 (JP) 2015-006085

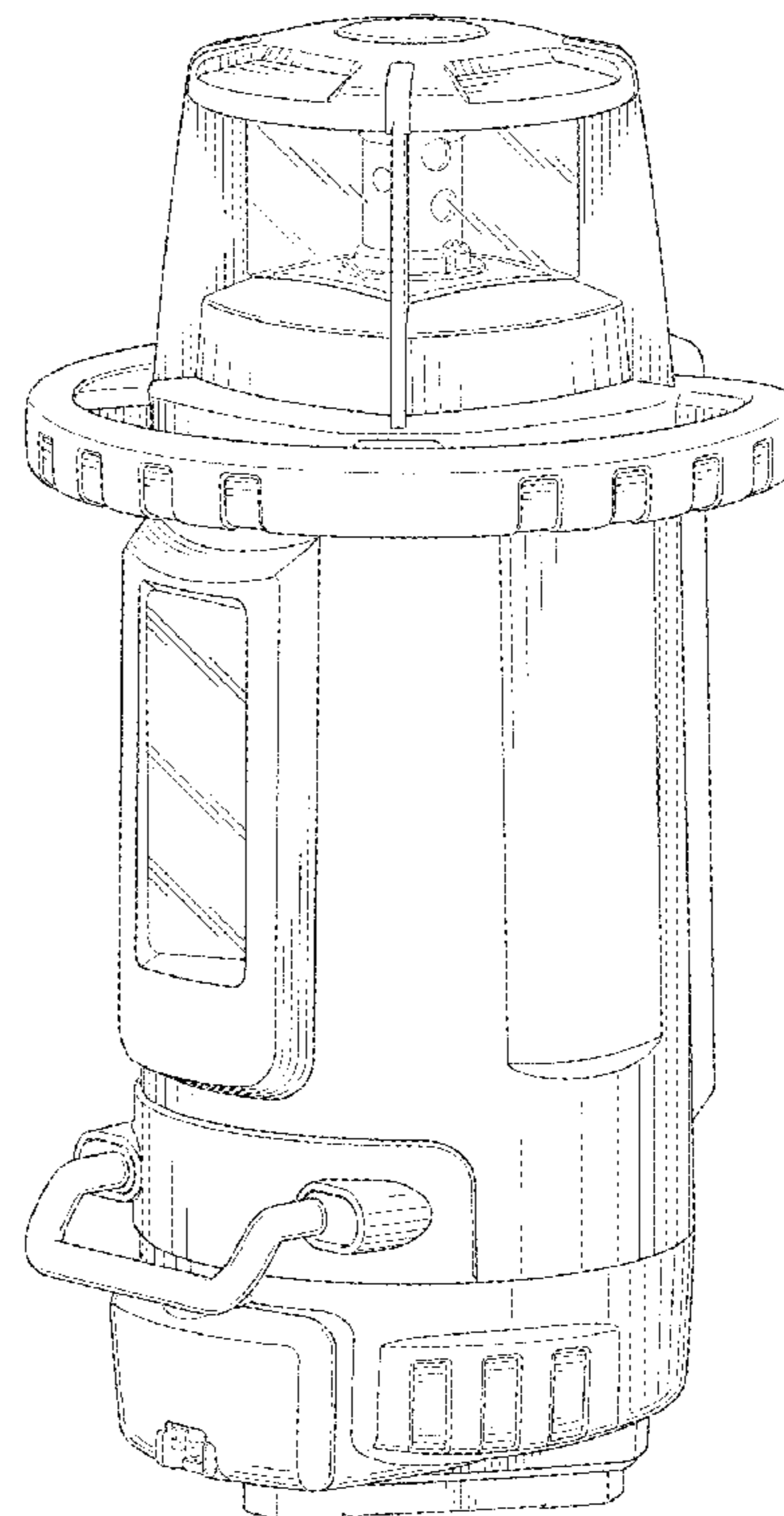
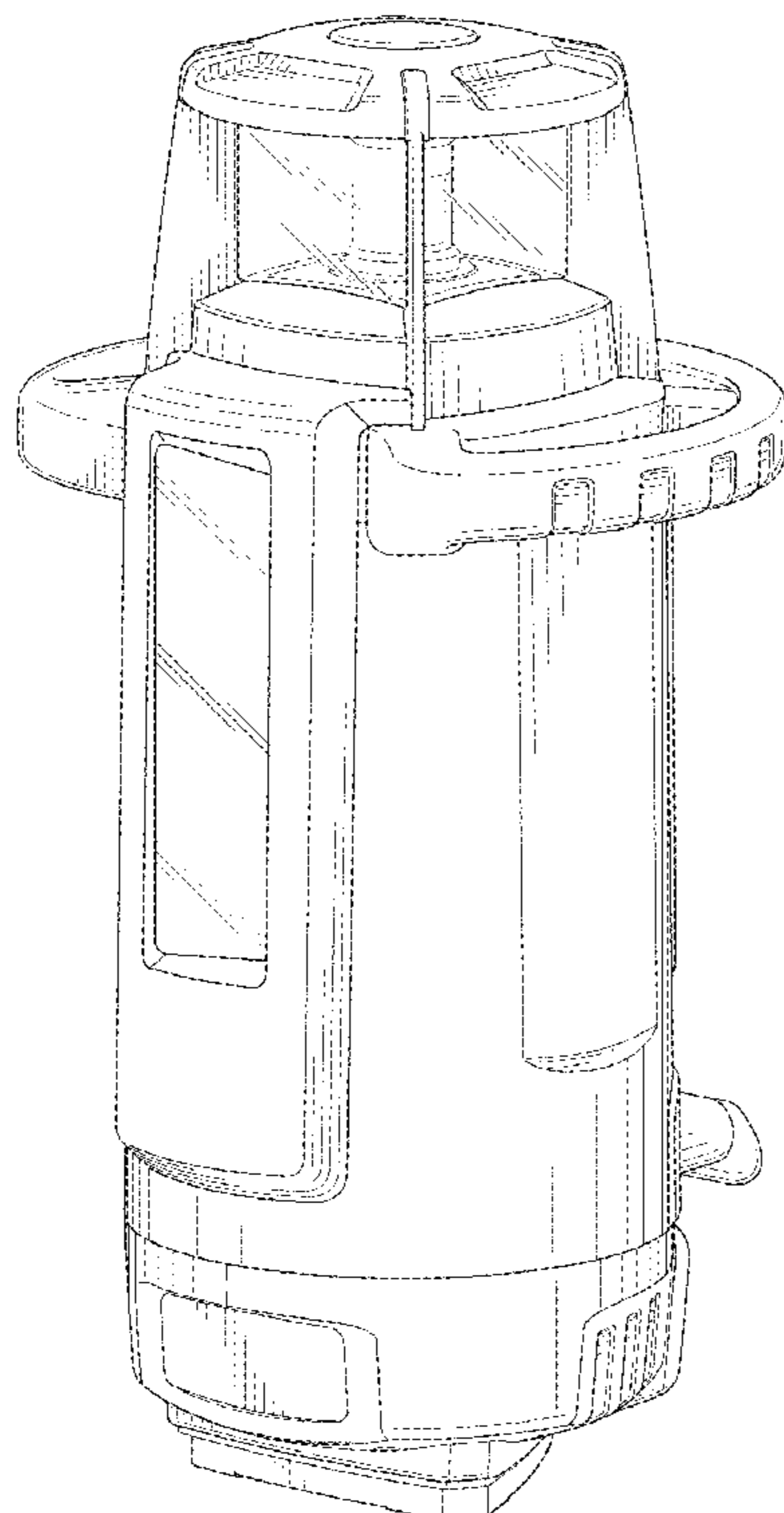
FIG. 1 is a front elevational view of the optical measuring theodolite using light wave;
FIG. 2 is a rear elevational view thereof;
FIG. 3 is a left-side elevational view thereof;
FIG. 4 is a right-side elevational view thereof;
FIG. 5 is a top plan view thereof;
FIG. 6 is a bottom plan view thereof;
FIG. 7 is a front, right-side, top perspective view thereof; and,
FIG. 8 is a rear, left-side, top perspective view thereof.
The broken lines depict environmental subject matter only and form no part of the claimed design.

(51) **LOC (10) Cl.** **10-04**

(52) **U.S. Cl.**
USPC **D10/66**

(58) **Field of Classification Search**
USPC D10/66

1 Claim, 7 Drawing Sheets



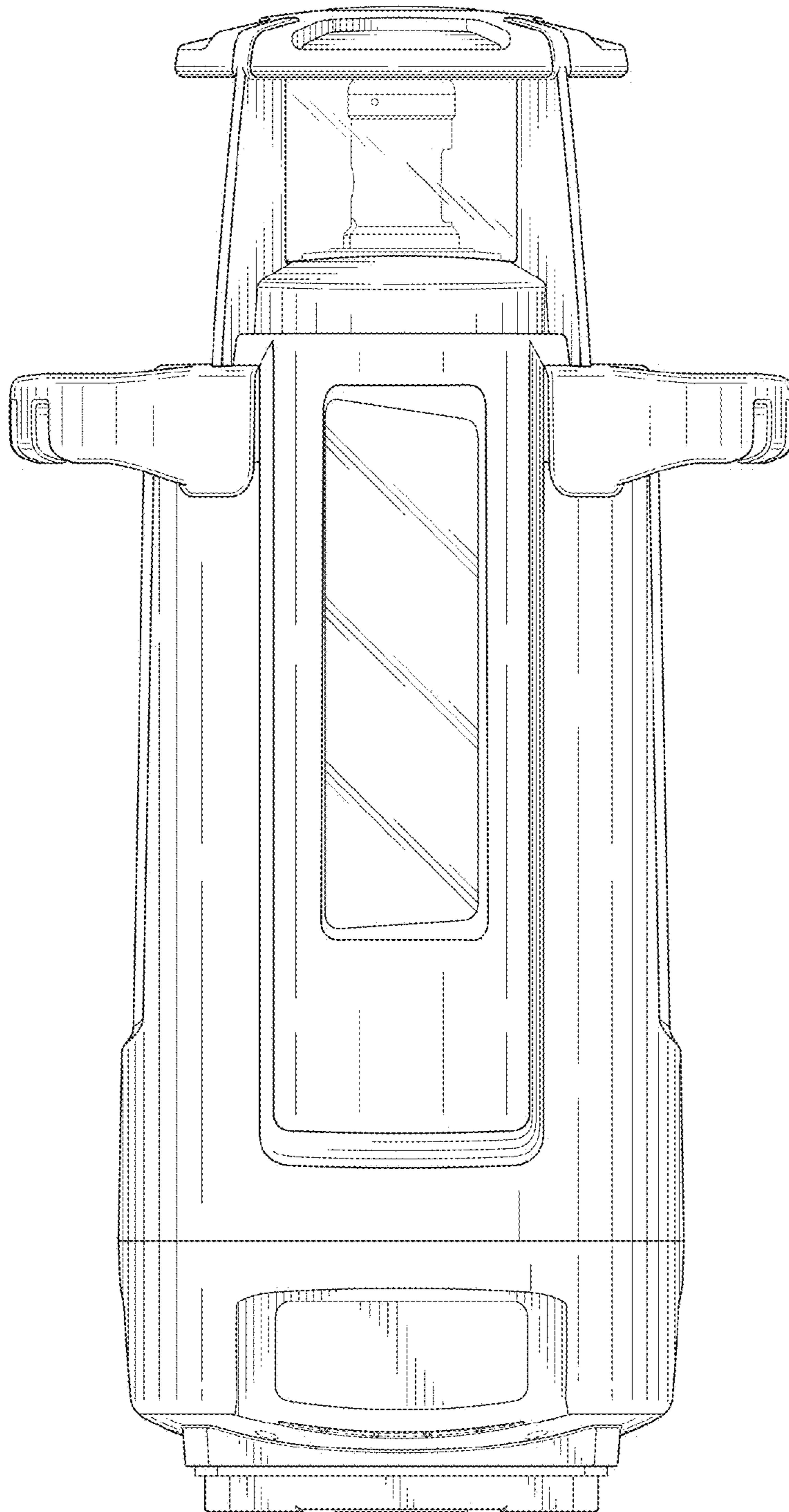


FIG. 1

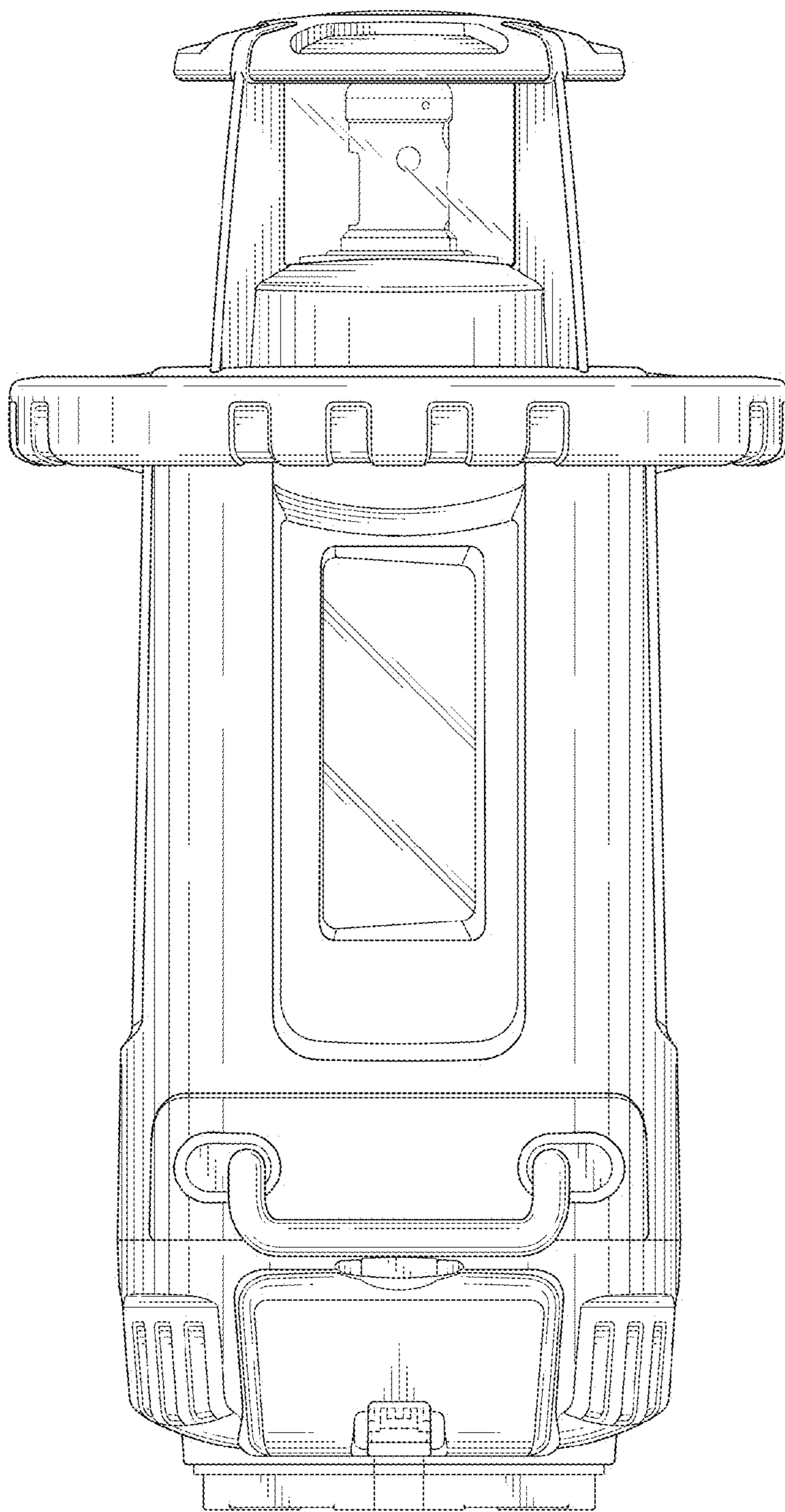


FIG. 2

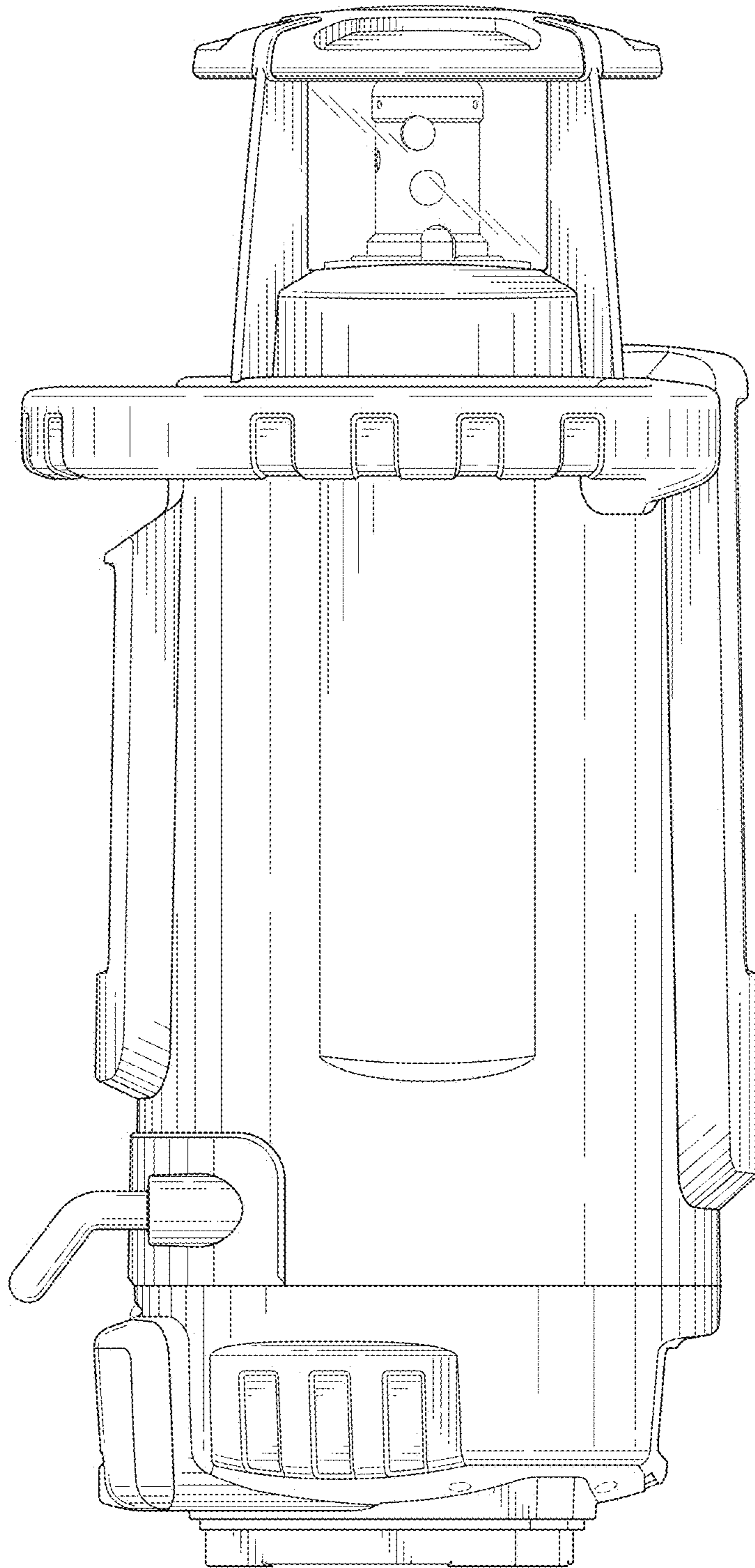


FIG. 3

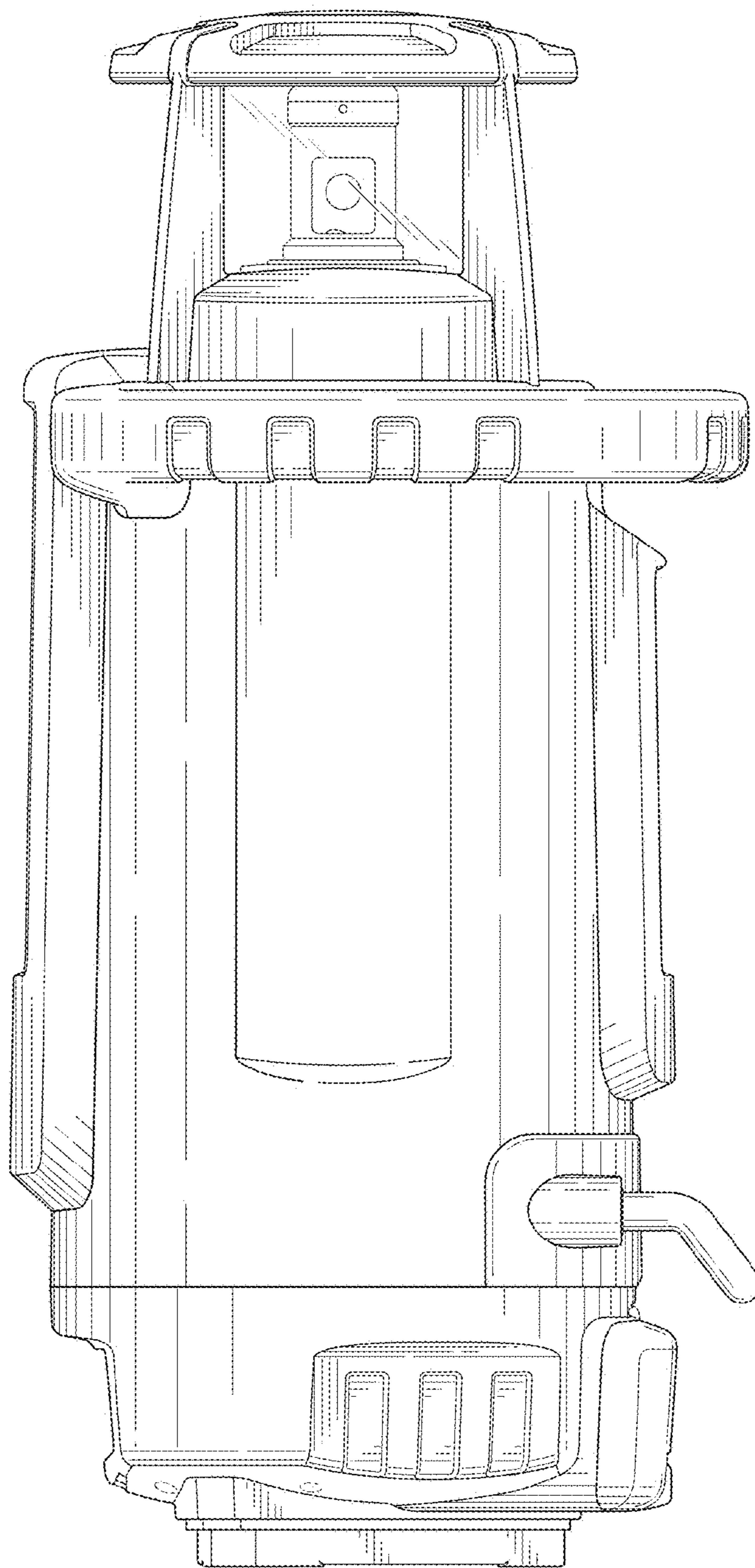


FIG. 4

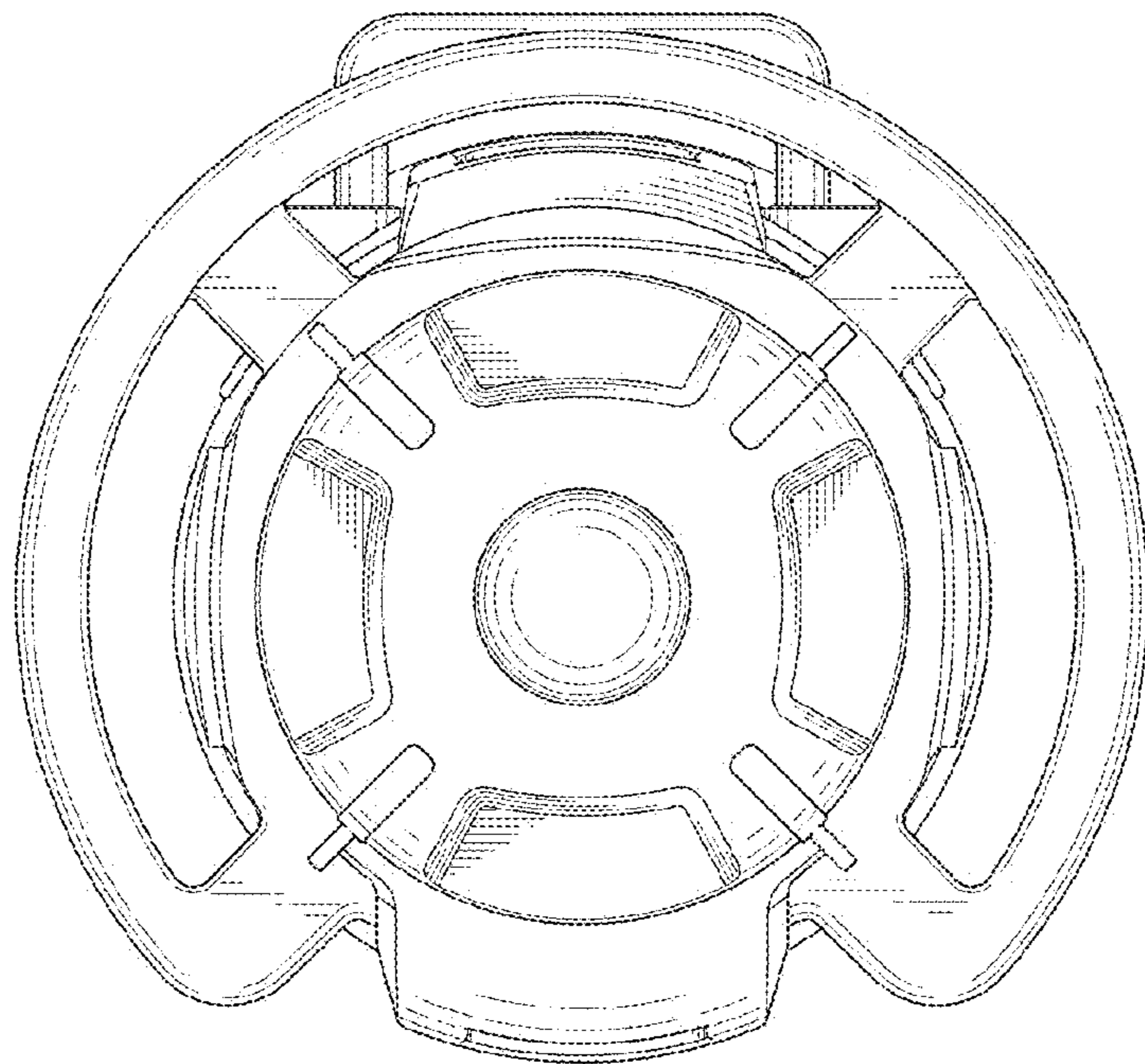


FIG. 5

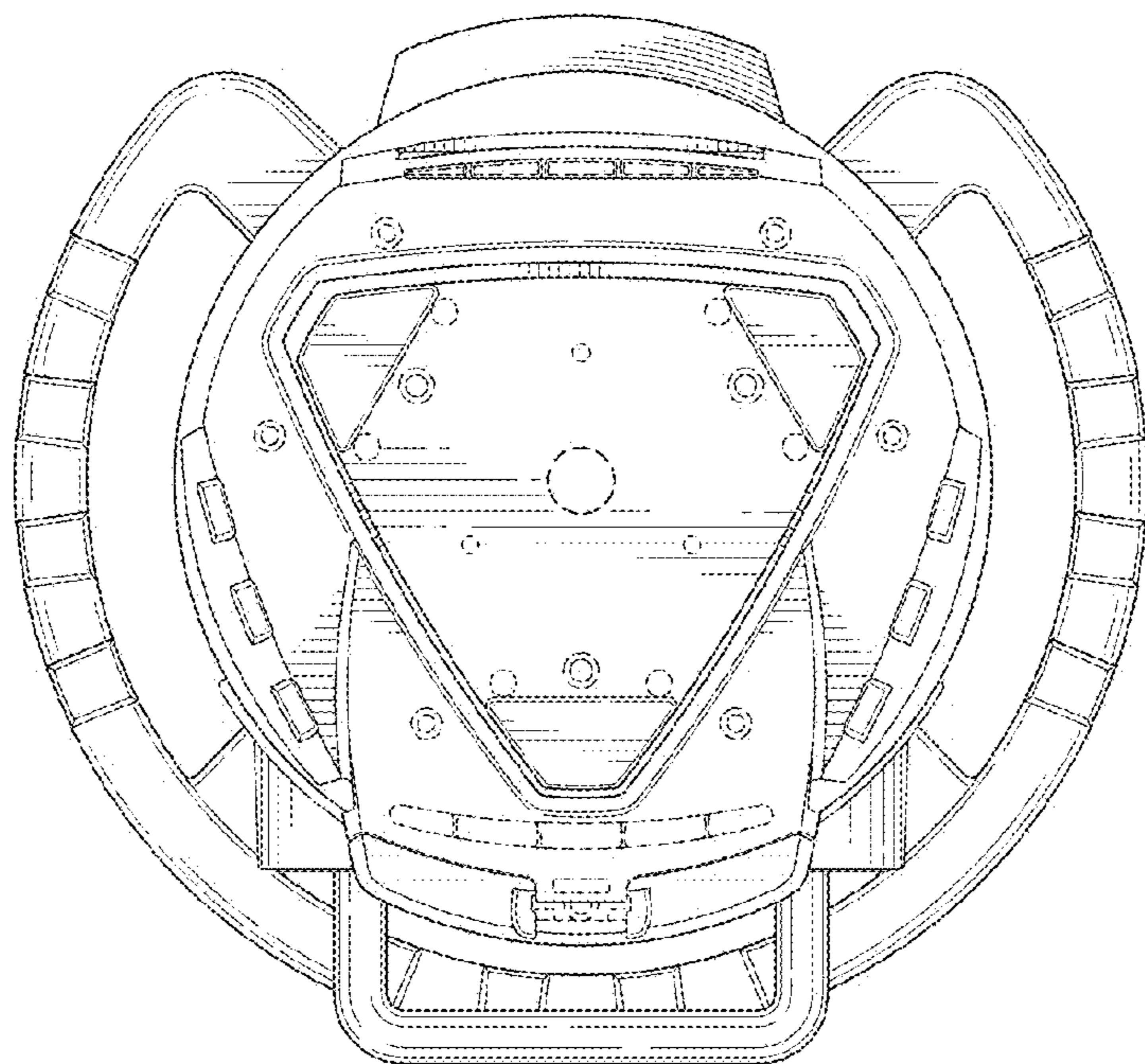


FIG. 6

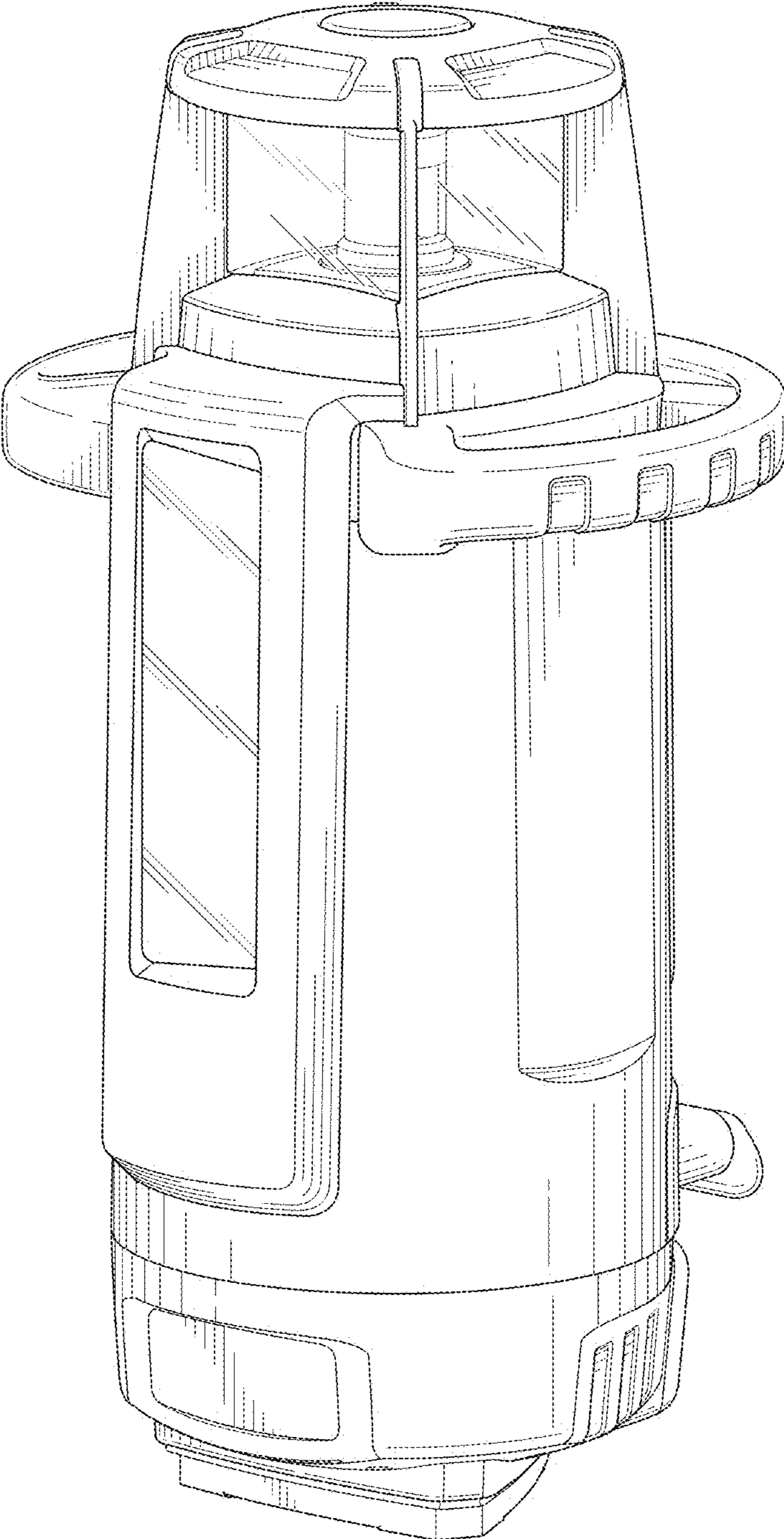


FIG. 7

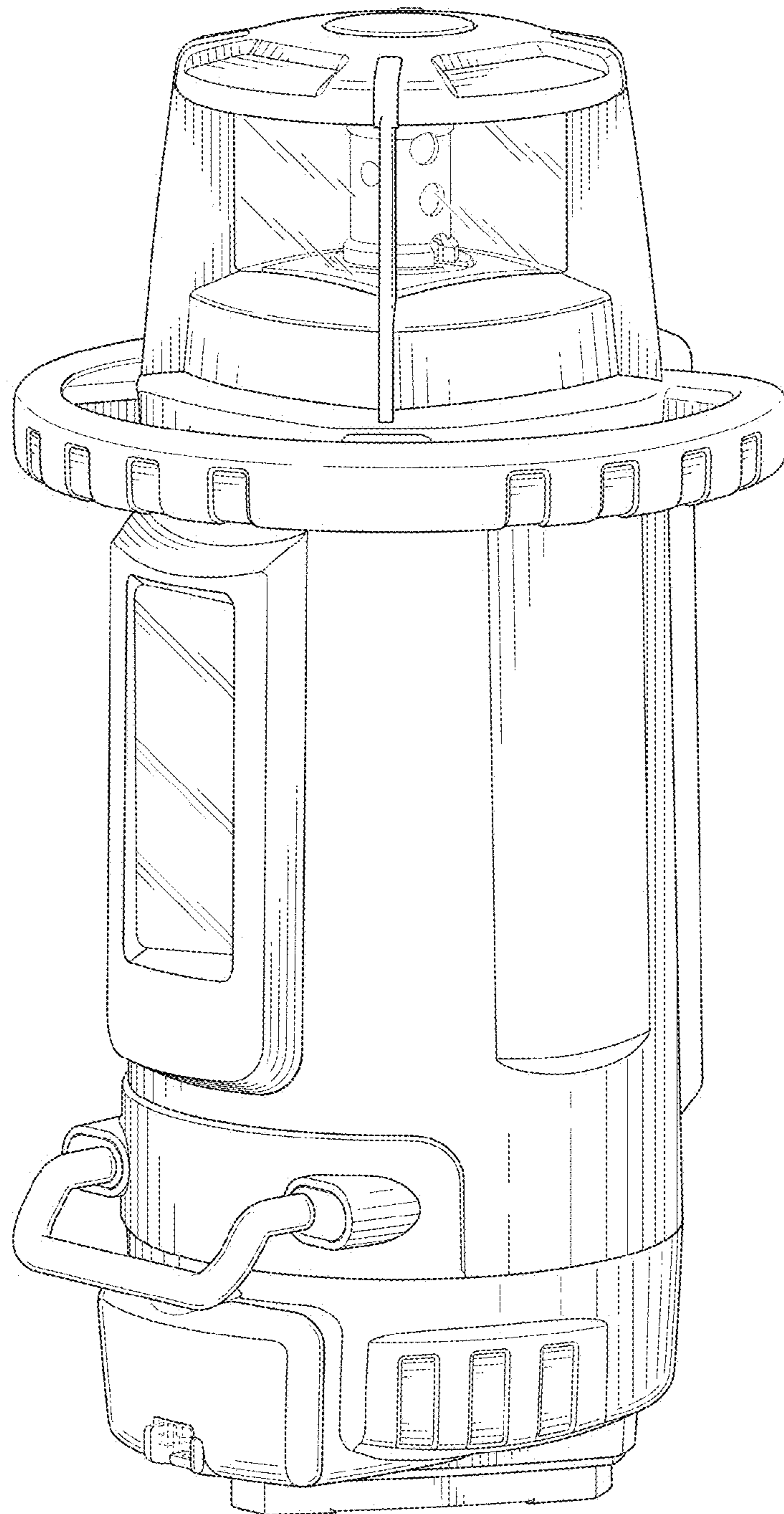


FIG. 8